

DXAFSを用いたfsダイナミクス研究

を目指して

阿部 仁

Photon Factory, IMSS, KEK

Outline

- Intro: XAFS, DXAFS
- A DXAFS study at NW2A, PF-AR
- Toward Laser Pump – DXAFS Probe experiments
- NW2A, PF-AR => Laser Compton Scattered X-ray, cERL
- Prospects for studies at cERL & 3-GeV ERL
- Summary

What is XAFS?

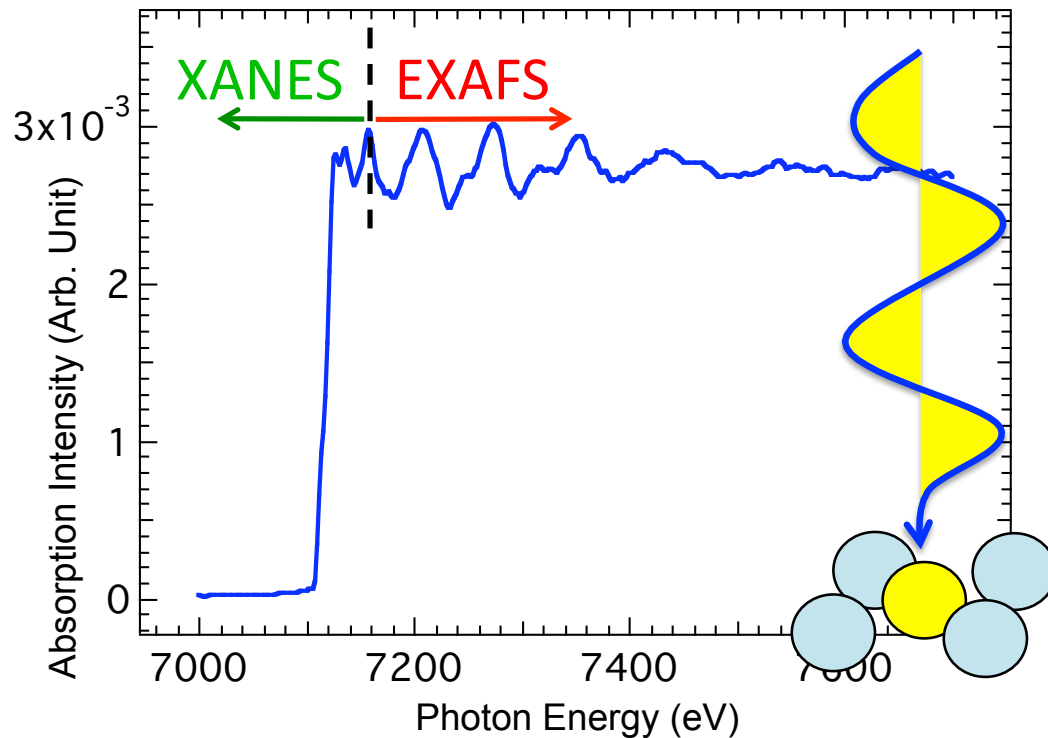
XAFS: **X**-ray **A**bsorption **F**ine **S**tructure

electronic state
(valence)
Symmetry

Bond length

Number of surrounding atoms (Coordination number)

Distribution, Thermal vibration



Element specific

to observe **Local structure**

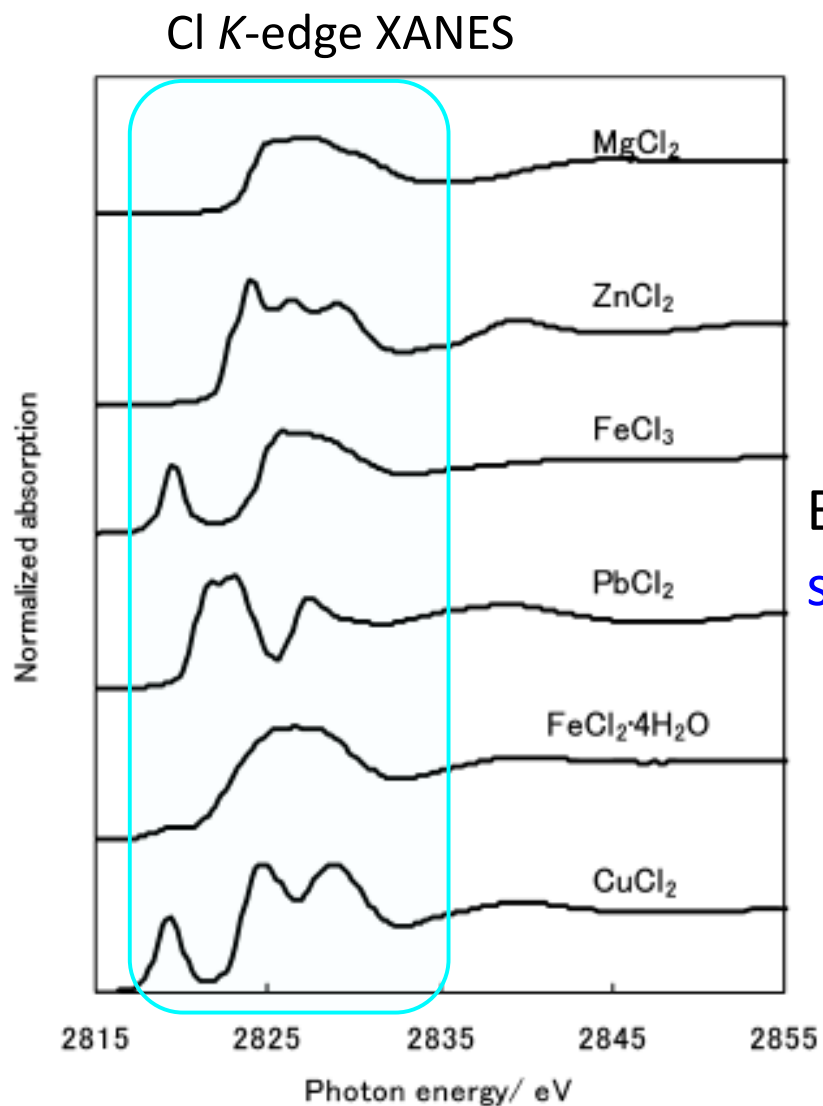
(long range periodicity is not required)

Solid, Liquid, Gas, whatever

XANES: X-ray Absorption Near Edge Structure

EXAFS: Extended X-ray Absorption Fine Structure

XANES tells us what your sample is.

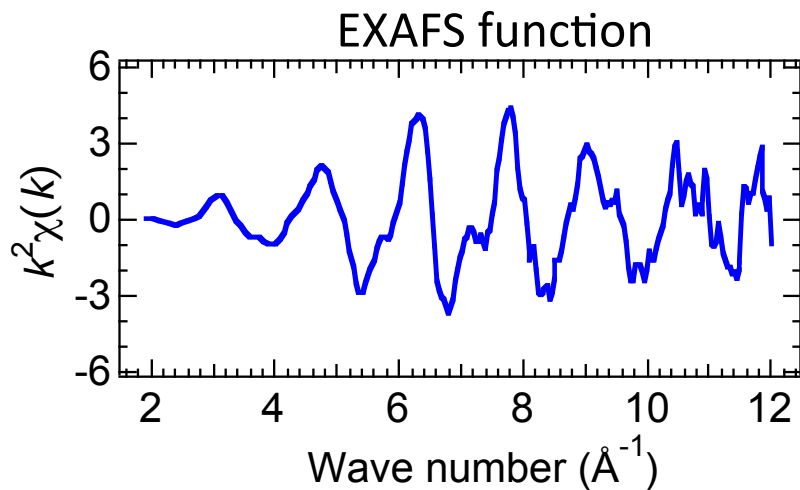
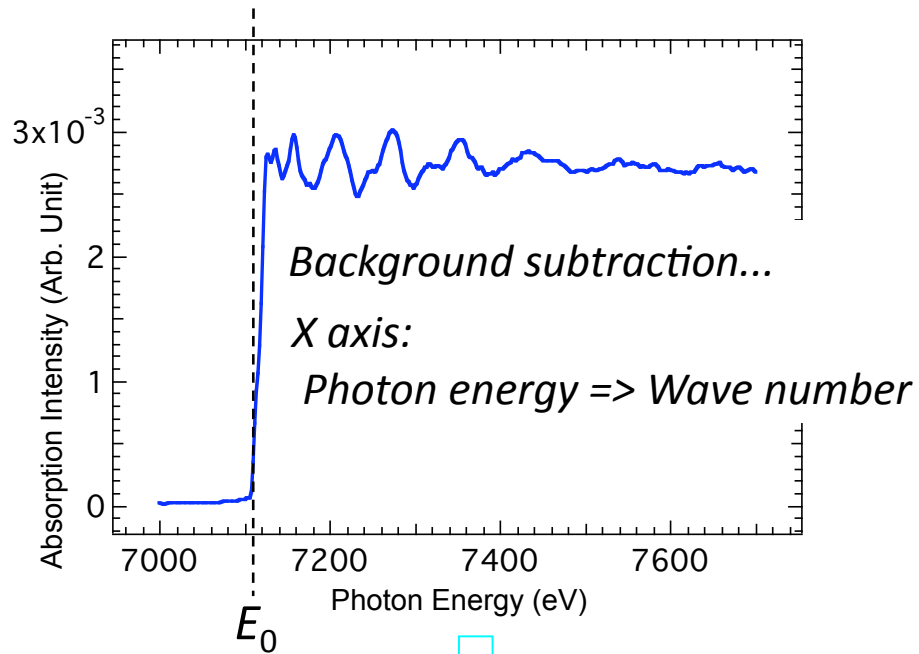


All these are metal chlorides.

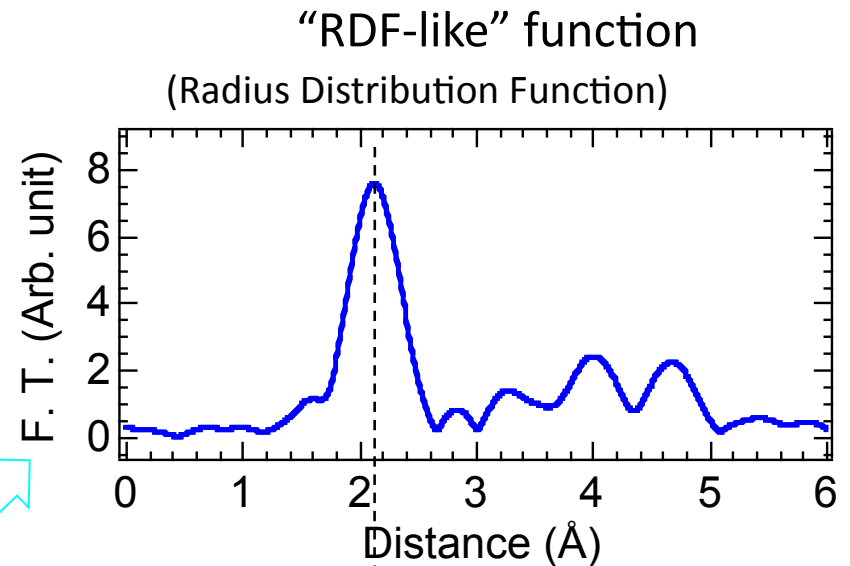
But you can see some **specific features** in each spectrum.

So you would recognize **what your sample is**.

How to Obtain Bond Length by EXAFS



Fourier Transform



Nearest neighbor atomic distance
+ phase shift

Bond length

Peak area

Coordination number

Eq. of single scattering EXAFS

$$\chi(k) = -S_0^2 \sum_j \frac{N_j}{kR_j^2} F_j(k) \exp(-2\sigma_j^2 k^2) \sin(2kR_j + 2\delta_{A,1}(k) + \varphi_j(k))$$

Amplitude Oscillation (phase)

"Round trip" of the wave

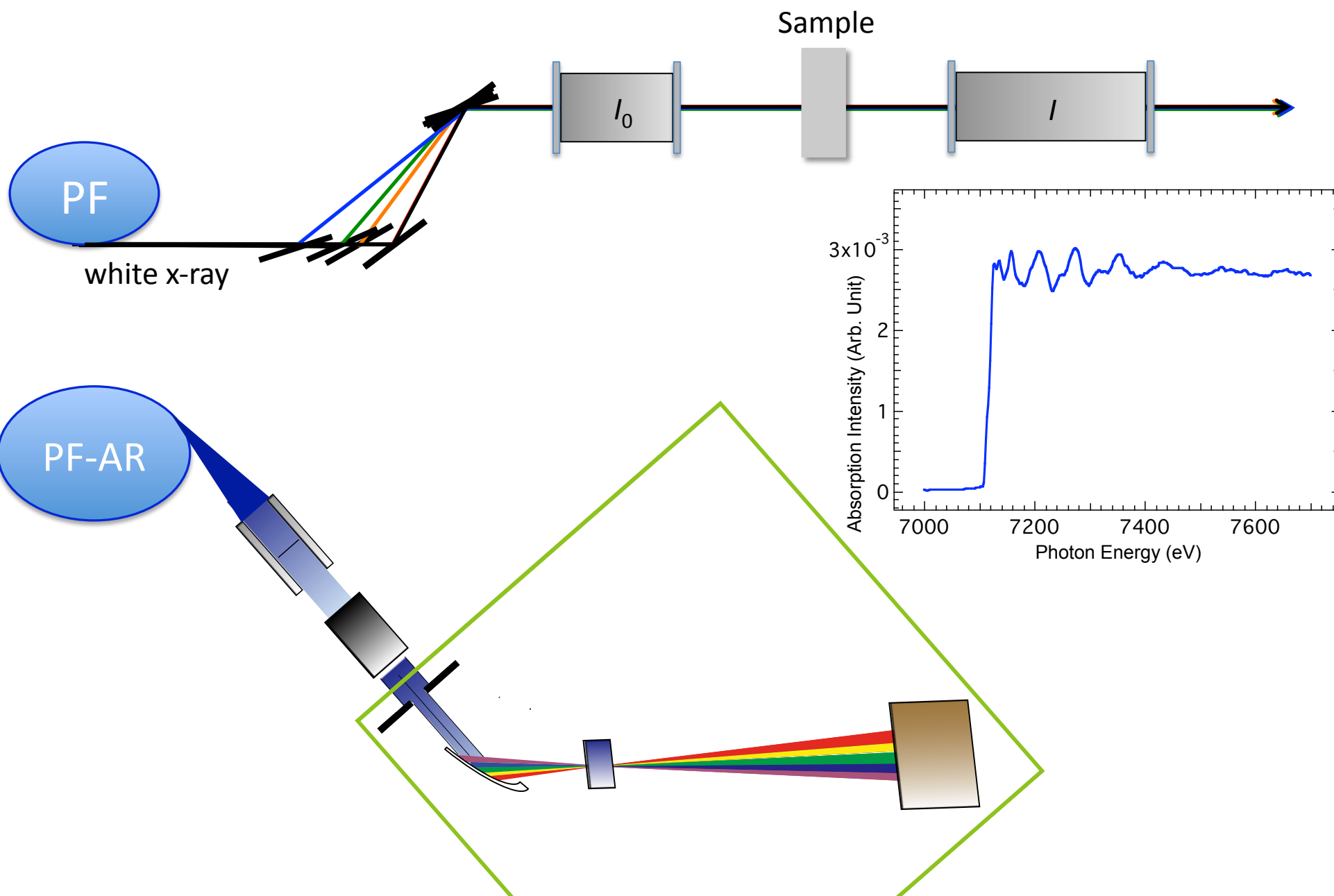
Phase shift
of absorbing atom
of scattering atom

Fourier Transform...
 Bond length R_j , etc.,

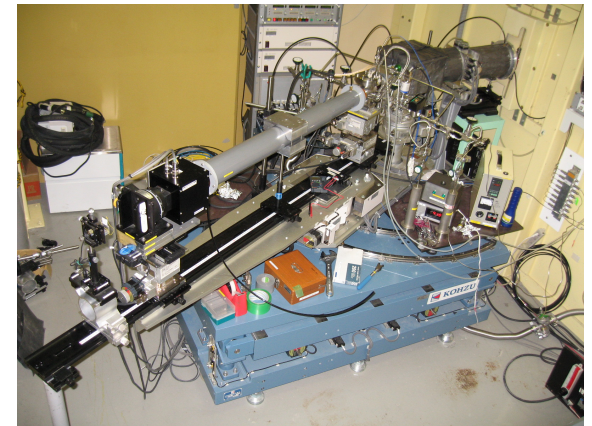
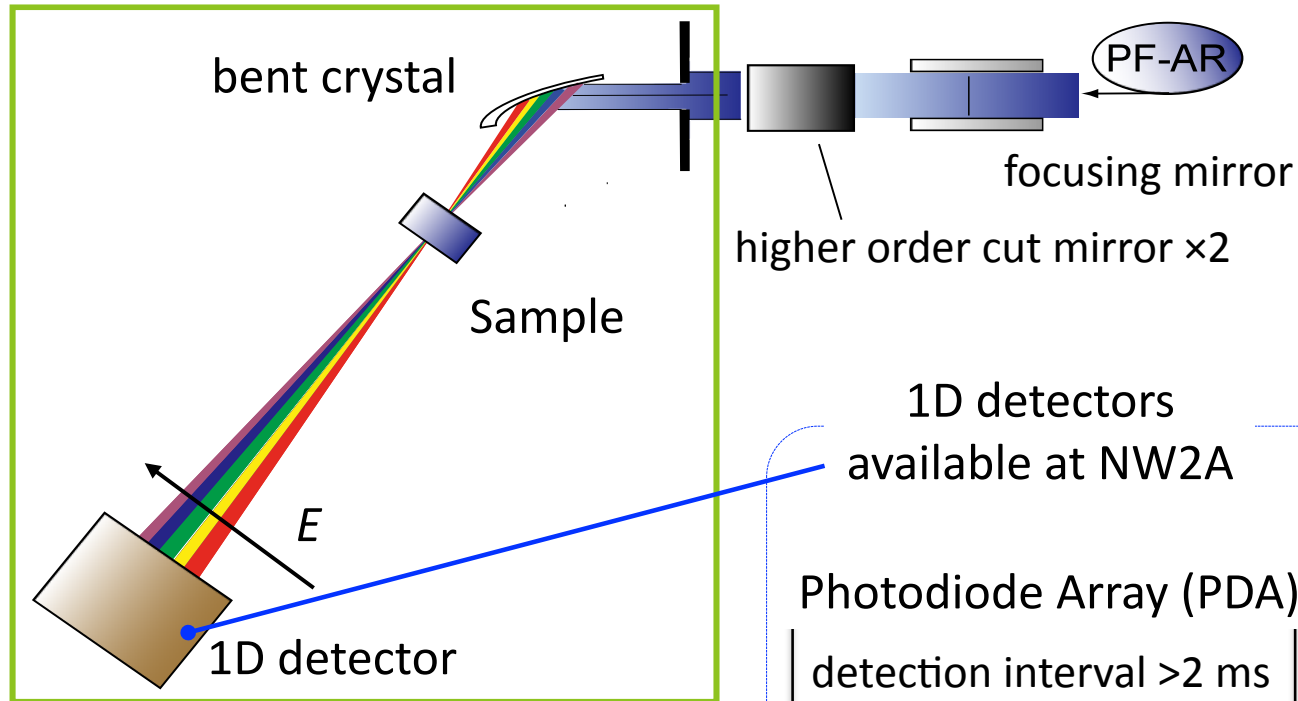
The diagram includes two graphs on the left. The top graph, labeled 'Isolated atom', shows a step-like function. The bottom graph, labeled 'Atom with neighbor', shows a step-like function followed by an oscillation. The x-axis for both is labeled 'E'. To the right, a diagram shows a central atom (blue dot) with an 'Outgoing Photoelectron' (blue arrow) and a 'Scattered Photoelectron' (black arrow) interacting with four surrounding atoms (purple dots). A distance R_0 is indicated between the central and one of the surrounding atoms. A large red arrow labeled 'Fourier Transform...' points downwards to the text 'Bond length R_j , etc.,'.

(Parameters high-lightened by yellow are fitting parameters.)

Step scan XAFS & DXAFS

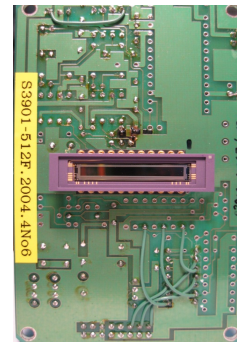


DXAFS at PF-AR NW2A

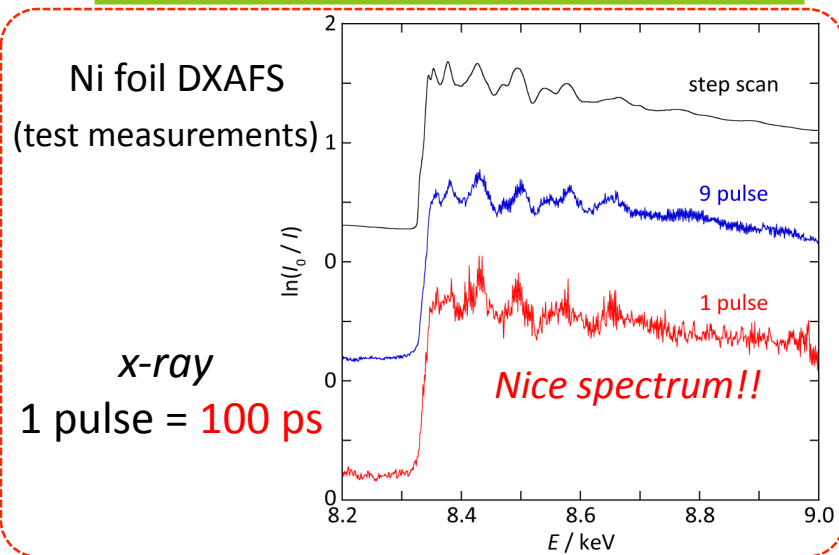
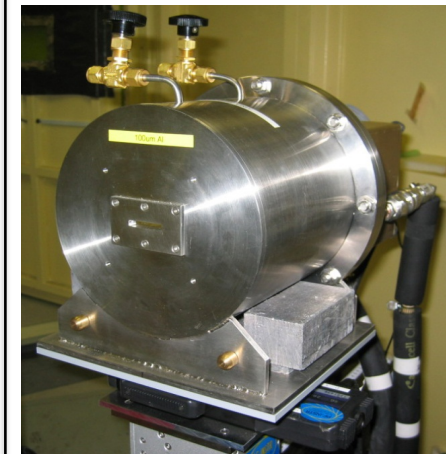


1D detectors
available at NW2A

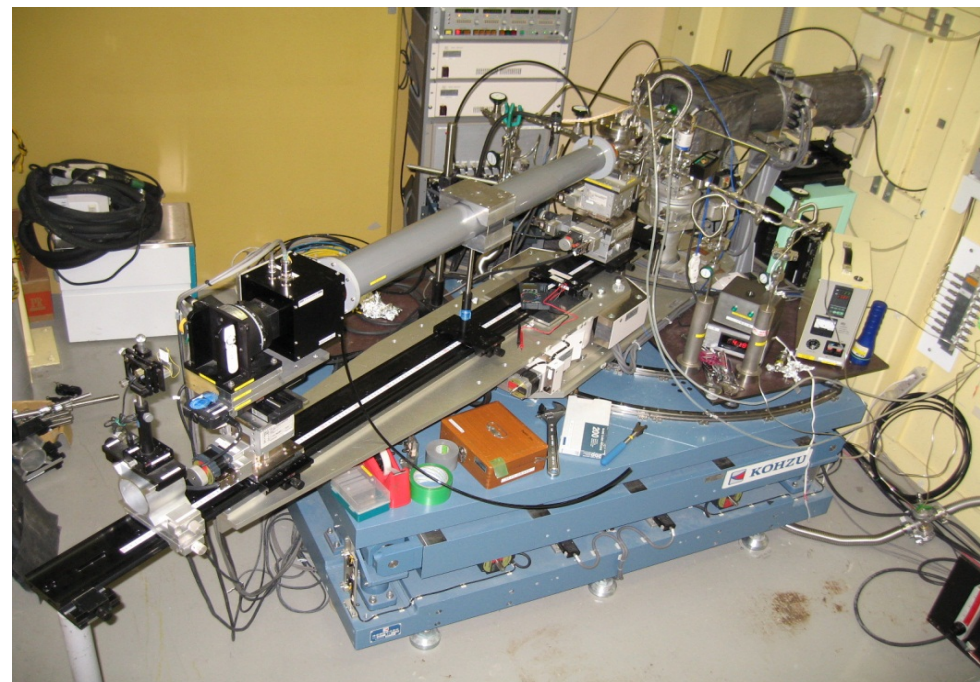
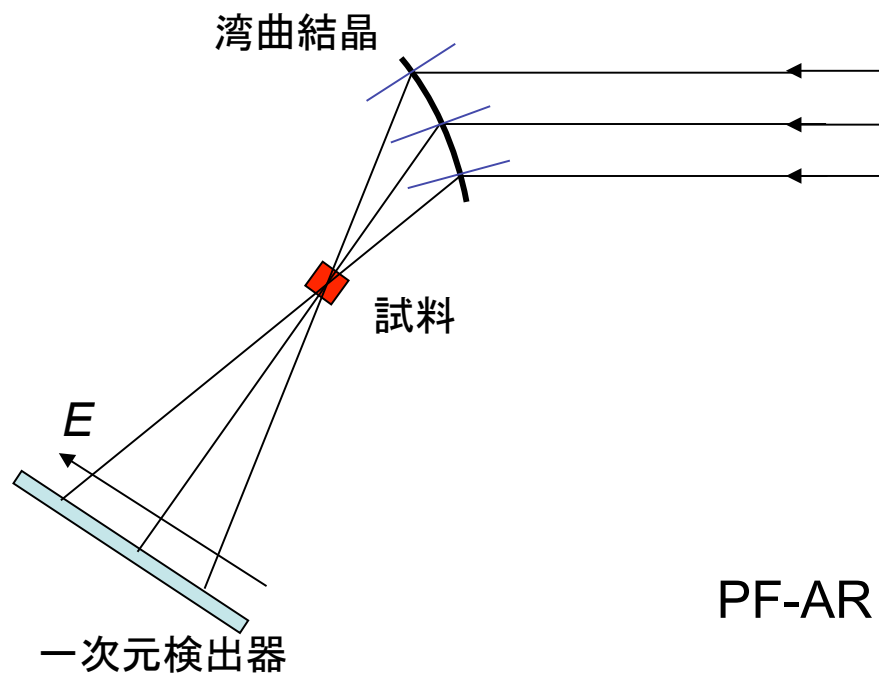
Photodiode Array (PDA)
detection interval > 2 ms
exposure time > 2 ms



XSTRIP (silicon microstrip)
detection interval > 23 μ s
exposure time > 0.5 μ s



DXAFS測定



PF-AR NW2A

ポリクロメーター 湾曲半径0.9 m
Si(511)
Laue配置

吸収端 Pd K (24.350 keV)

一次元検出器 蛍光体付フォトダイオードアレイ
時間分解能 10 ms



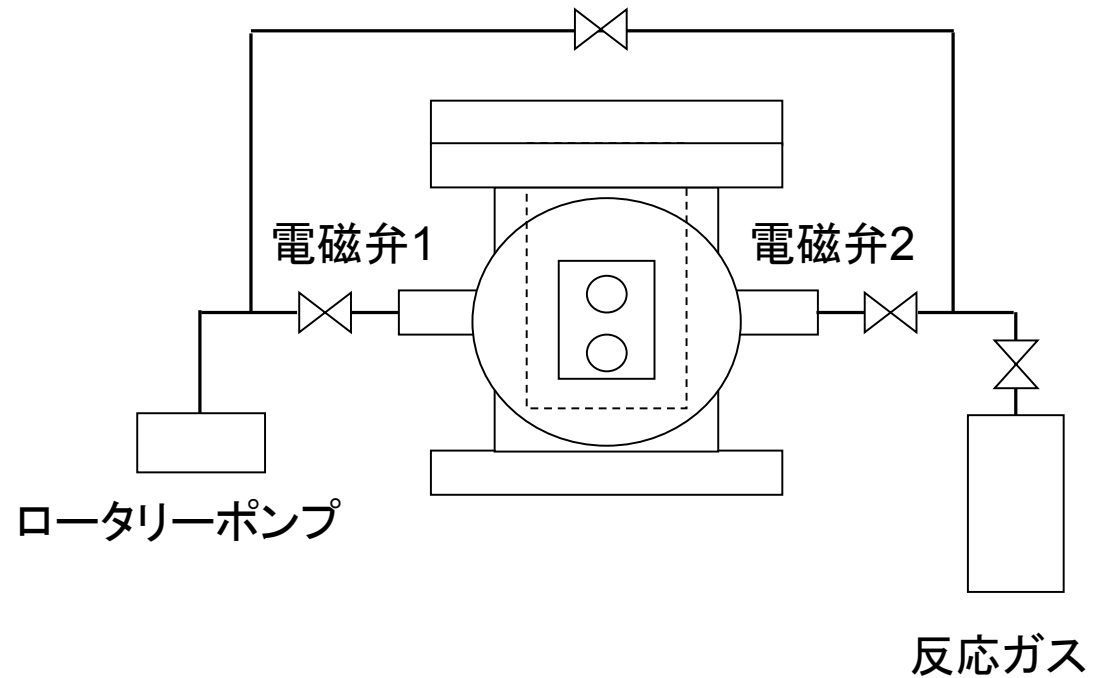
試料 γ -アルミナ担持パラジウム (Pd担持量3 wt%)

還元反応 水素 (4.0~49.5 kPa) 試料温度 573, 623, 673 K
一酸化炭素 (4.5~49.1 kPa) 試料温度 673, 723, 773 K

酸化反応 酸素 (4.1~61.8 kPa)、 試料温度 573, 623, 673, 723, 773 K

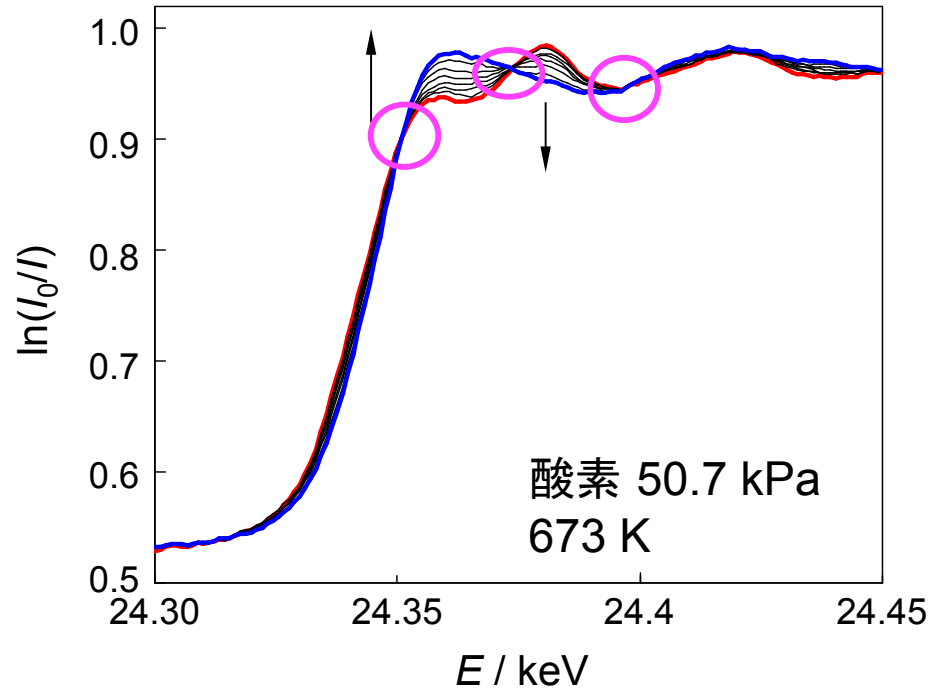


*in situ*セル



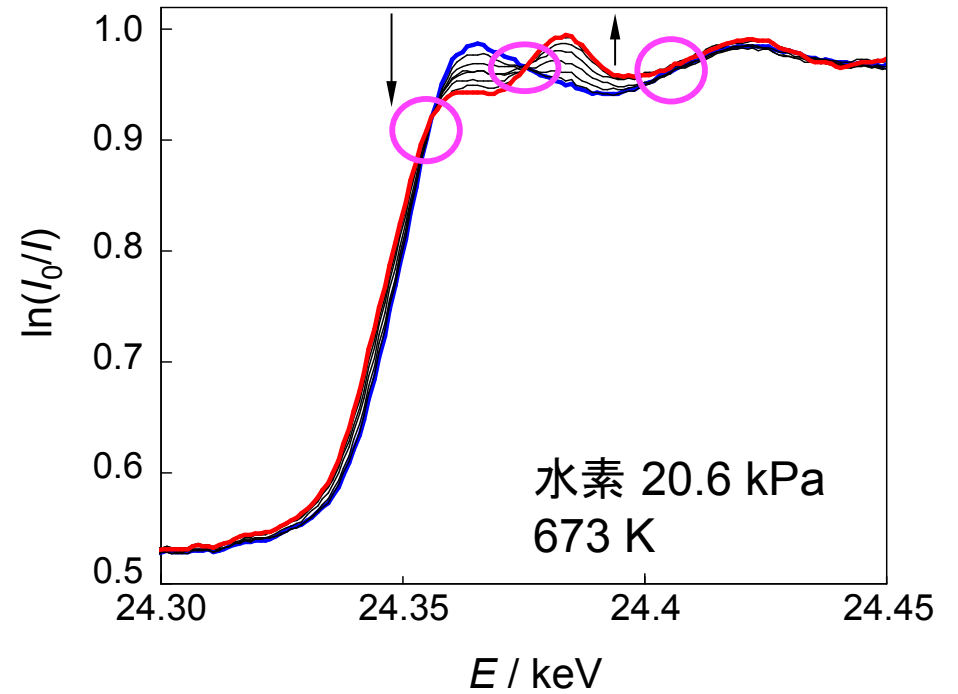
時間分解XANESスペクトル

酸化反応



Pd — PdO

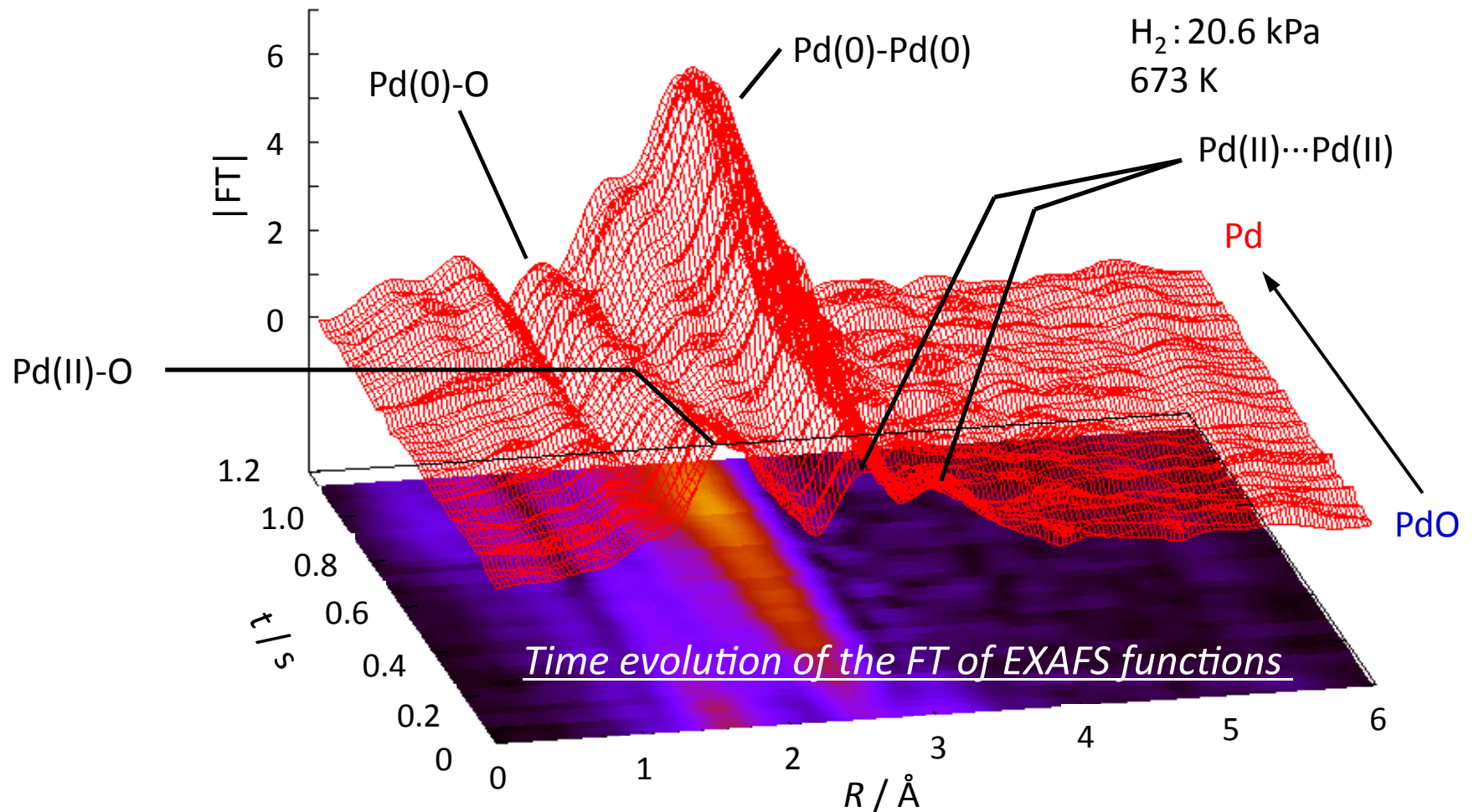
還元反応

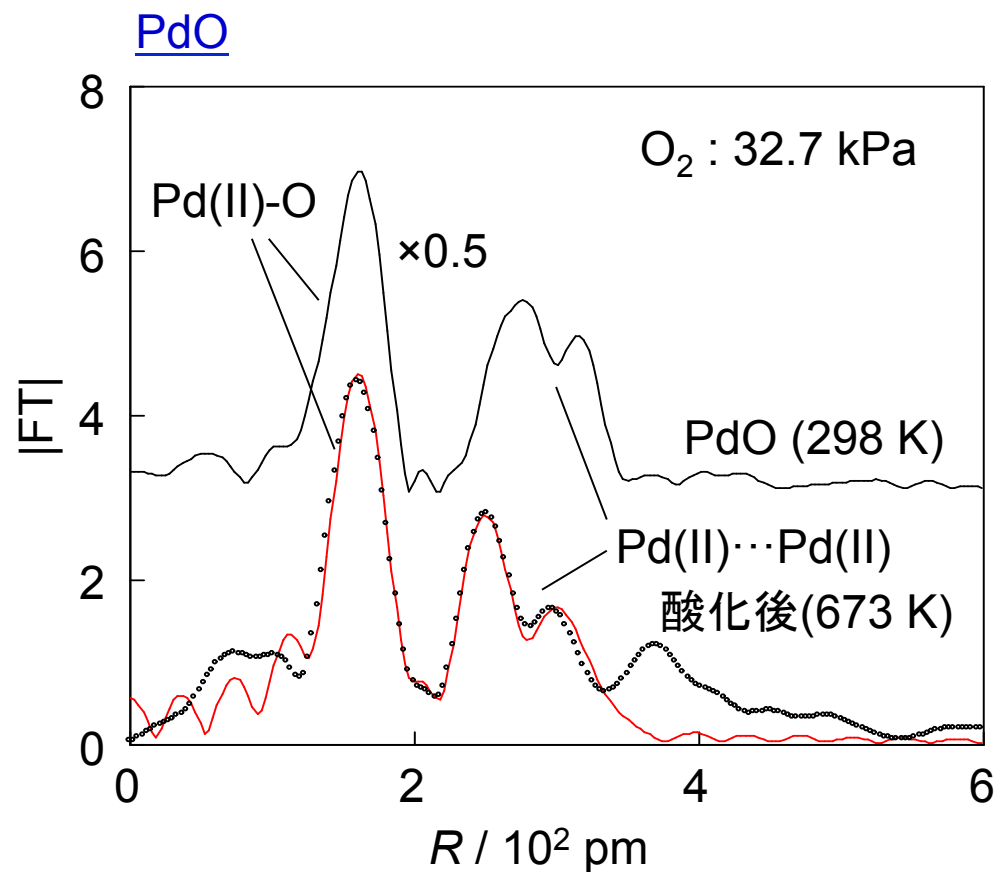
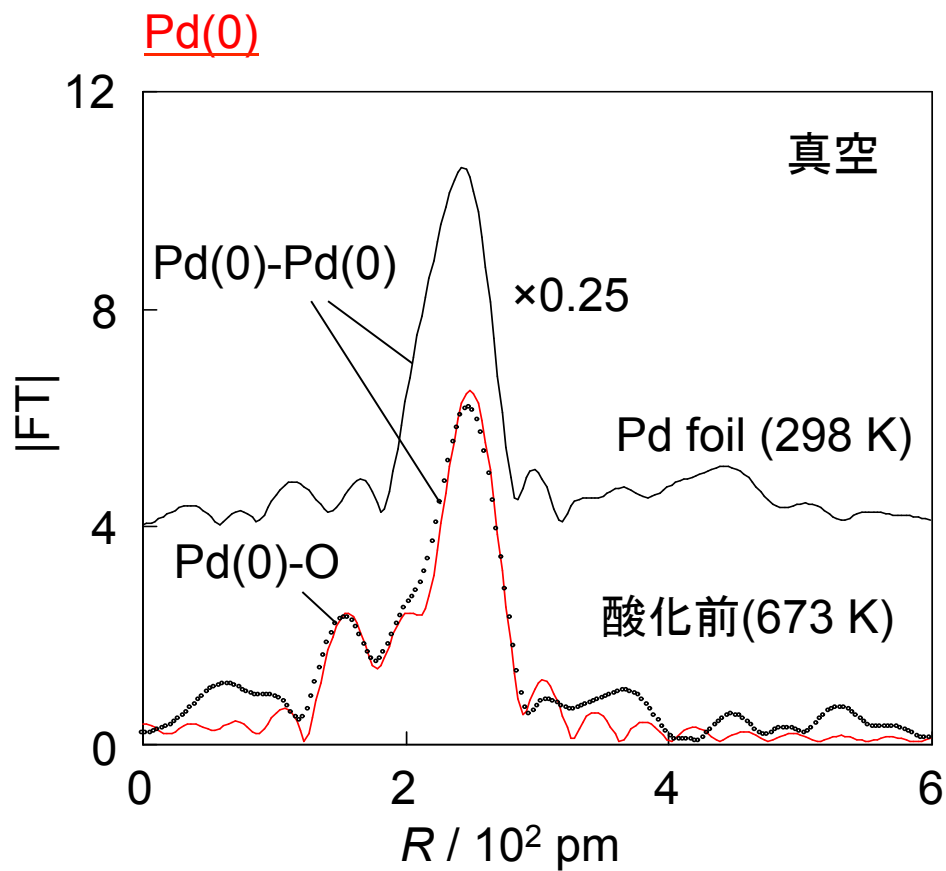


PdO — Pd

Real time observation of PdO -> Pd reduction reaction

Pd (3wt%) supported by γ -Al₂O₃, Pd K-edge (24.3 keV) EXAFS
PDA detector, recorded every 10 ms





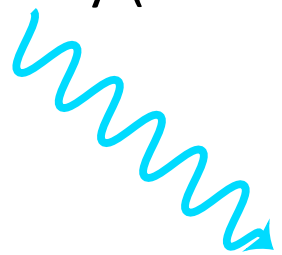
		N	R / pm
Pd(0)	Pd(0)-O	0.7	202
	Pd(0)-Pd(0)	5.6	270
Pd foil	Pd(0)-Pd(0)	12*	274

		N	R / pm
PdO	Pd(II)-O	2.1	205
	Pd(0)···Pd(0)	1.1	287
	Pd(0)···Pd(0)	2.2	337
PdO reference	Pd(II)-O	4*	204
	Pd(0)···Pd(0)	4*	304
	Pd(0)···Pd(0)	8*	342

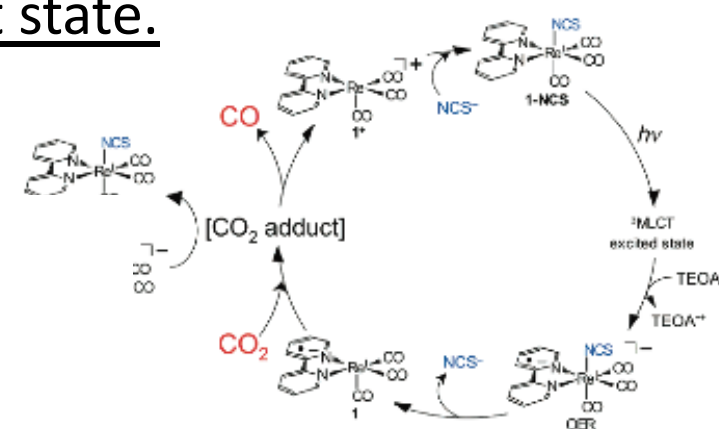
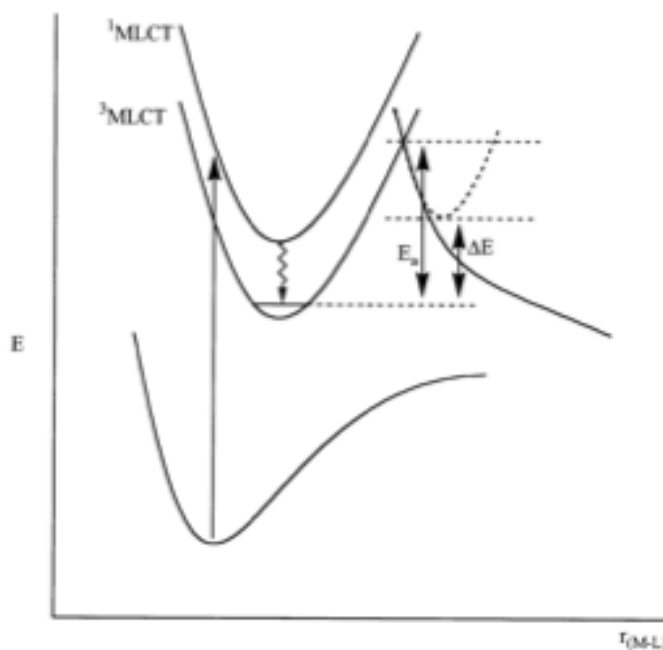
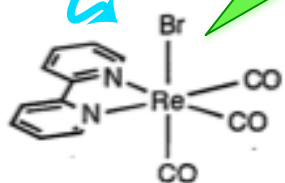
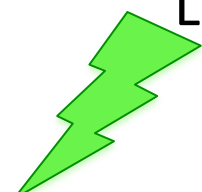
Laser Pump – DXAFS Probe experiments

We've just started to try to measure this experiment
as to capture a transient state.

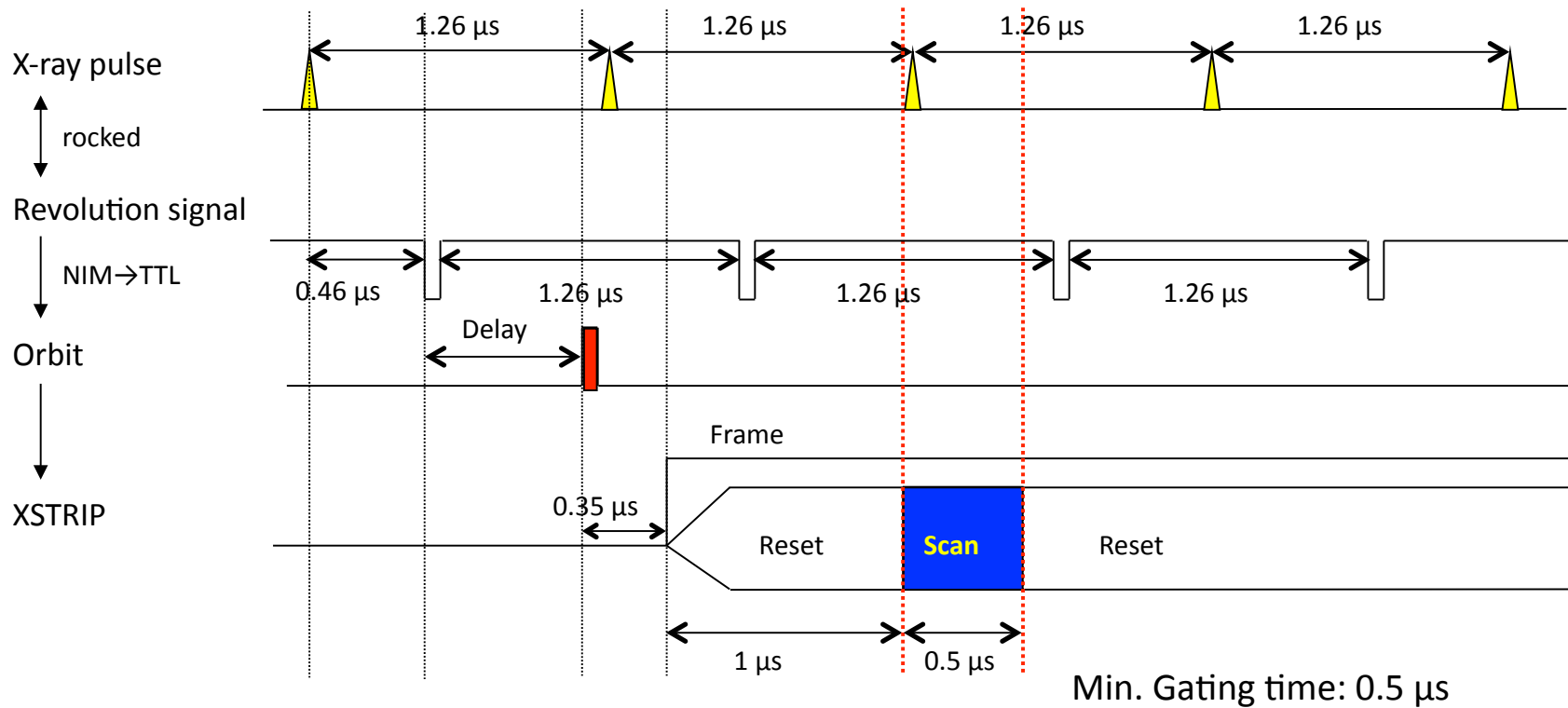
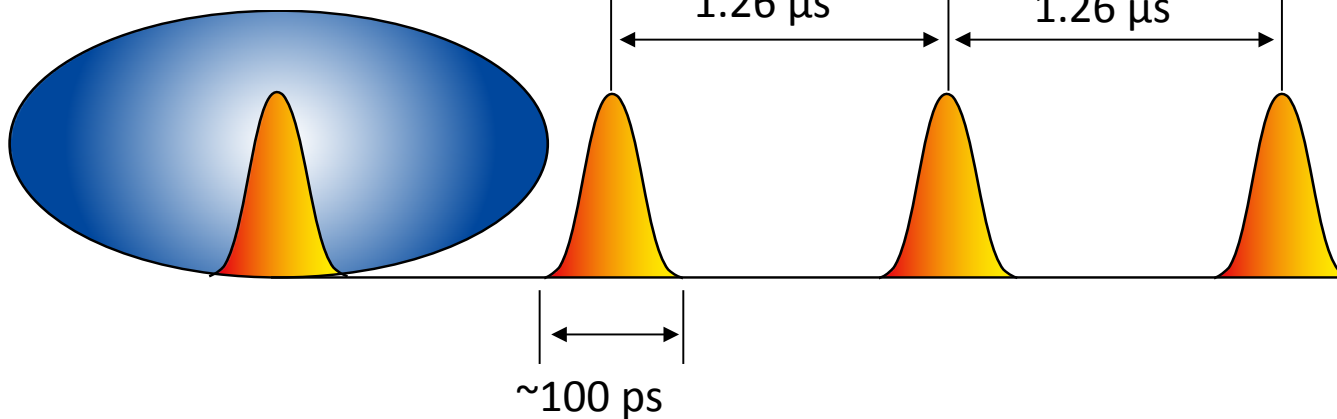
X-ray (DXAFS)

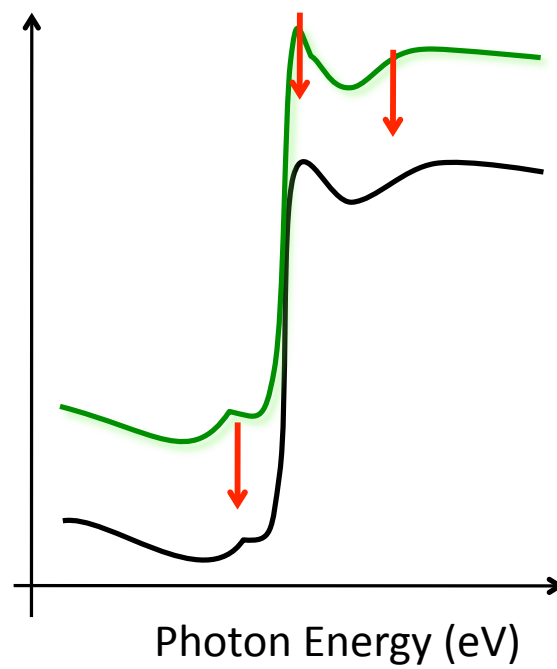
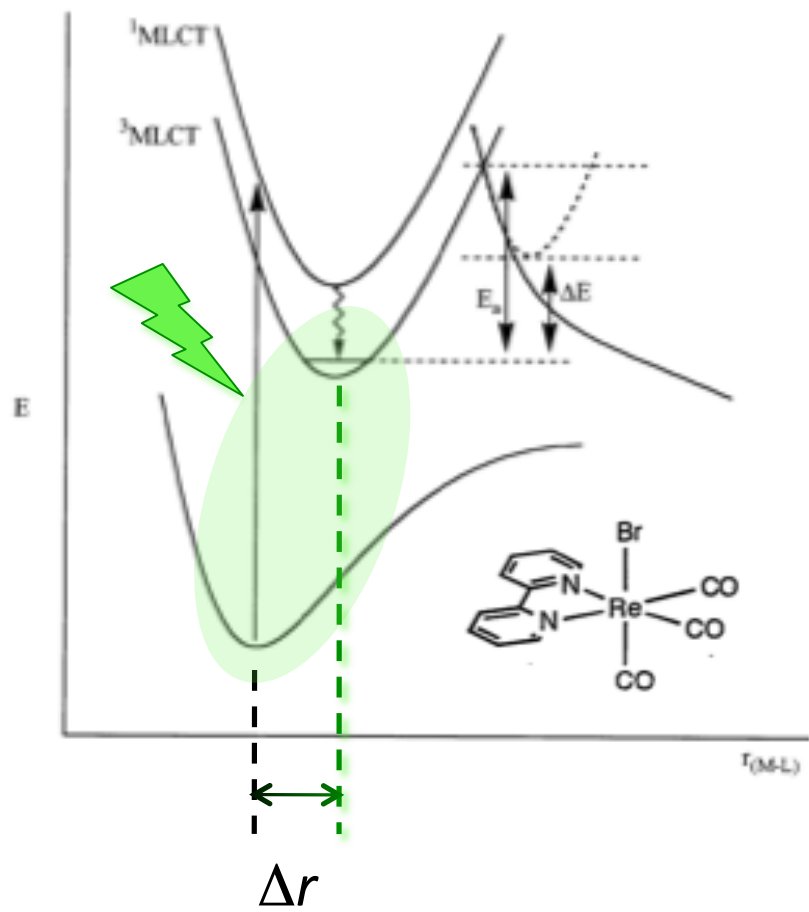


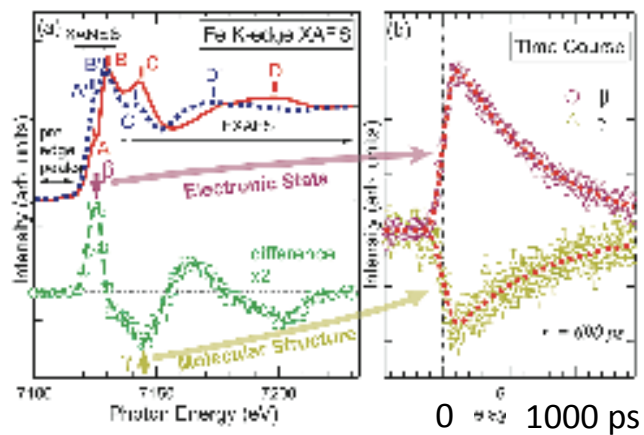
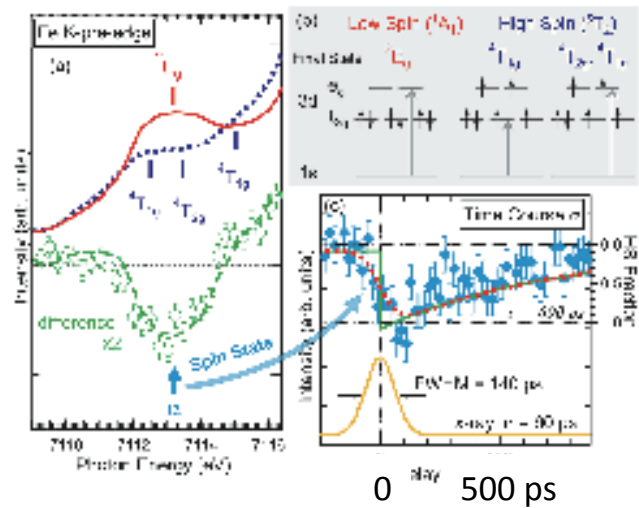
Laser



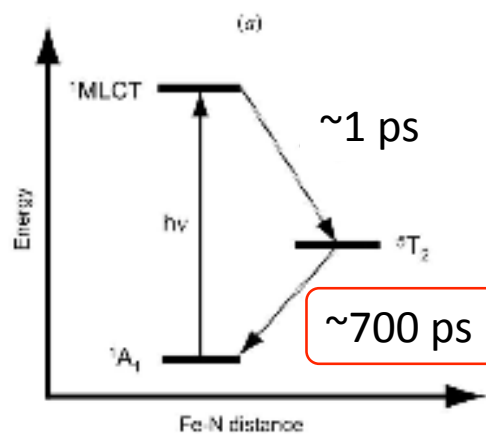
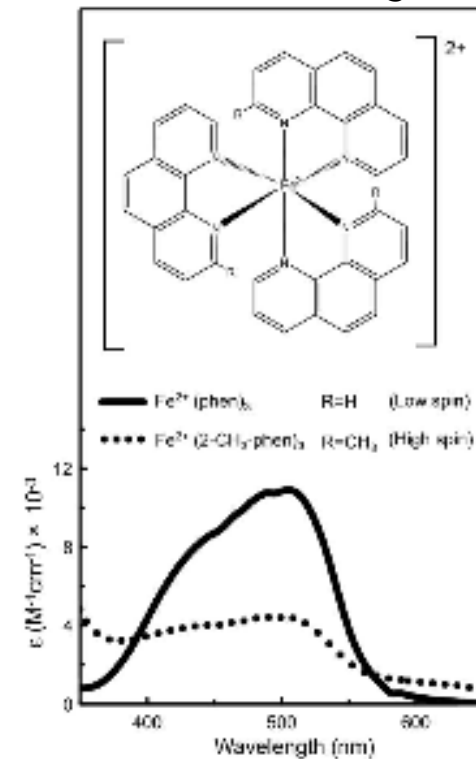
PF-AR







S. Nozawa, et al., JACS **132**, 61 (2010)

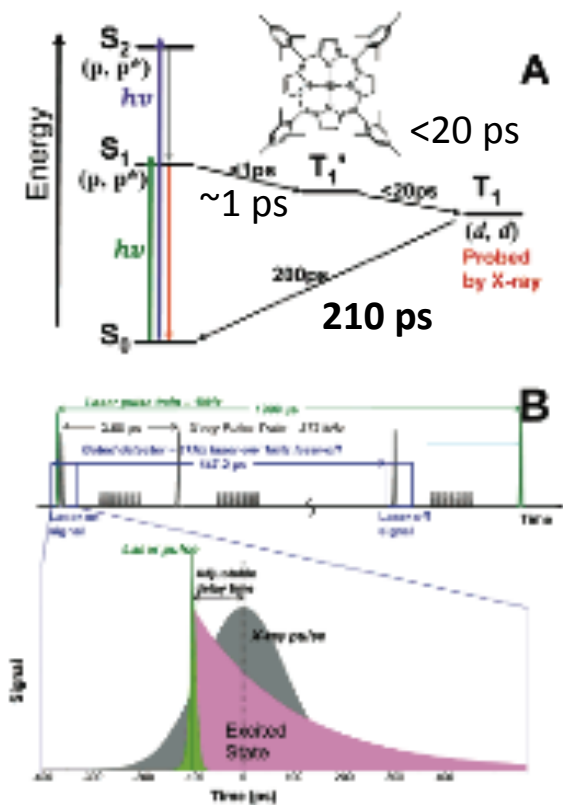


T. Sato, et al., J. Synchrotron Rad. **16**, 110 (2009)

Limitations at NW2A, PF-AR

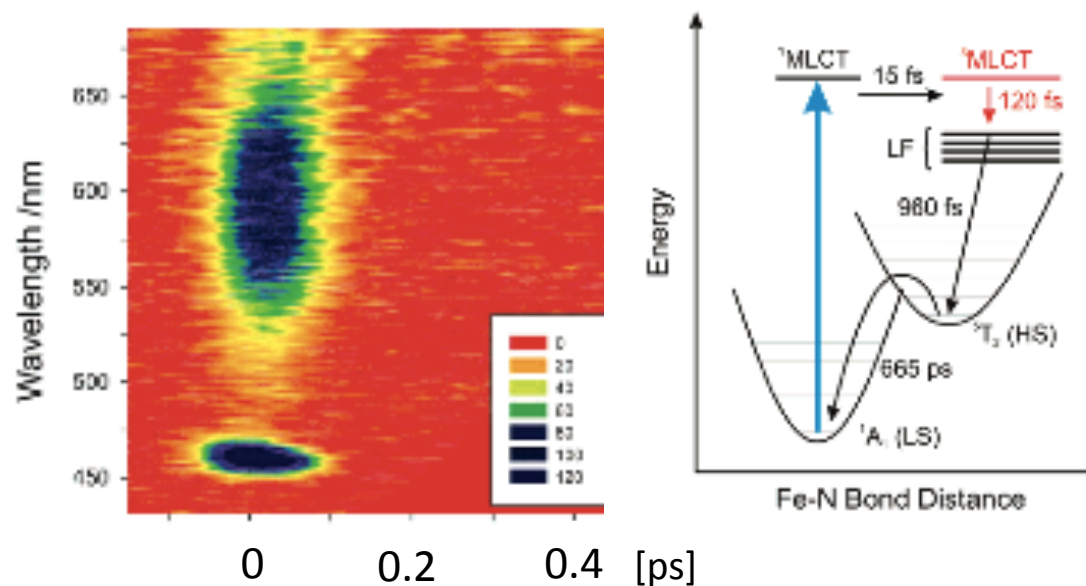
- Phenomena faster than the pulse duration of PF-AR (~ 100 ps) cannot be detected.
- The jitter between laser & x-ray always exists, and would be more serious when we go shorter time resolution.
- Many experimental apparatuses are put in the hatch one after another.

Some TR experiments in the world



Lin X. Chen, et al., JACS **129**, 9616 (2007)

Luminescence spectra of aq. $[\text{Fe}^{\text{II}}(\text{bpy})_3]^{2+}$



W. Gawelda, et al., JACS **129**, 8199 (2007)

What's the suitable sources for DXAFS?

Source	Photons/pulse/ 0.1%BW	Photn Flux /s	Duration	Rep rate
3 rd generation SR	10 ⁴⁻⁶	10 ¹⁰⁻¹²	~100 ps	< ~500 MHz
Laser slicing at BM	10 ¹⁻³	10 ⁴⁻⁷	~100-1000 fs	1-10 kHz
Laser Compton Scattered X-ray, cERL	10 ³⁻⁴	10 ⁶⁻⁷	~100 fs	1 kHz
ERL	10 ⁵⁻⁶	10 ¹⁴⁻¹⁵	~100 fs – 1ps	1.3 GHz
XFEL	10 ¹¹⁻¹²	10 ¹³⁻¹⁵	~10-100 fs	~100 Hz

DXAFS should be equipped and performed
at the **cERL**, and then the **3-GeV ERL**.

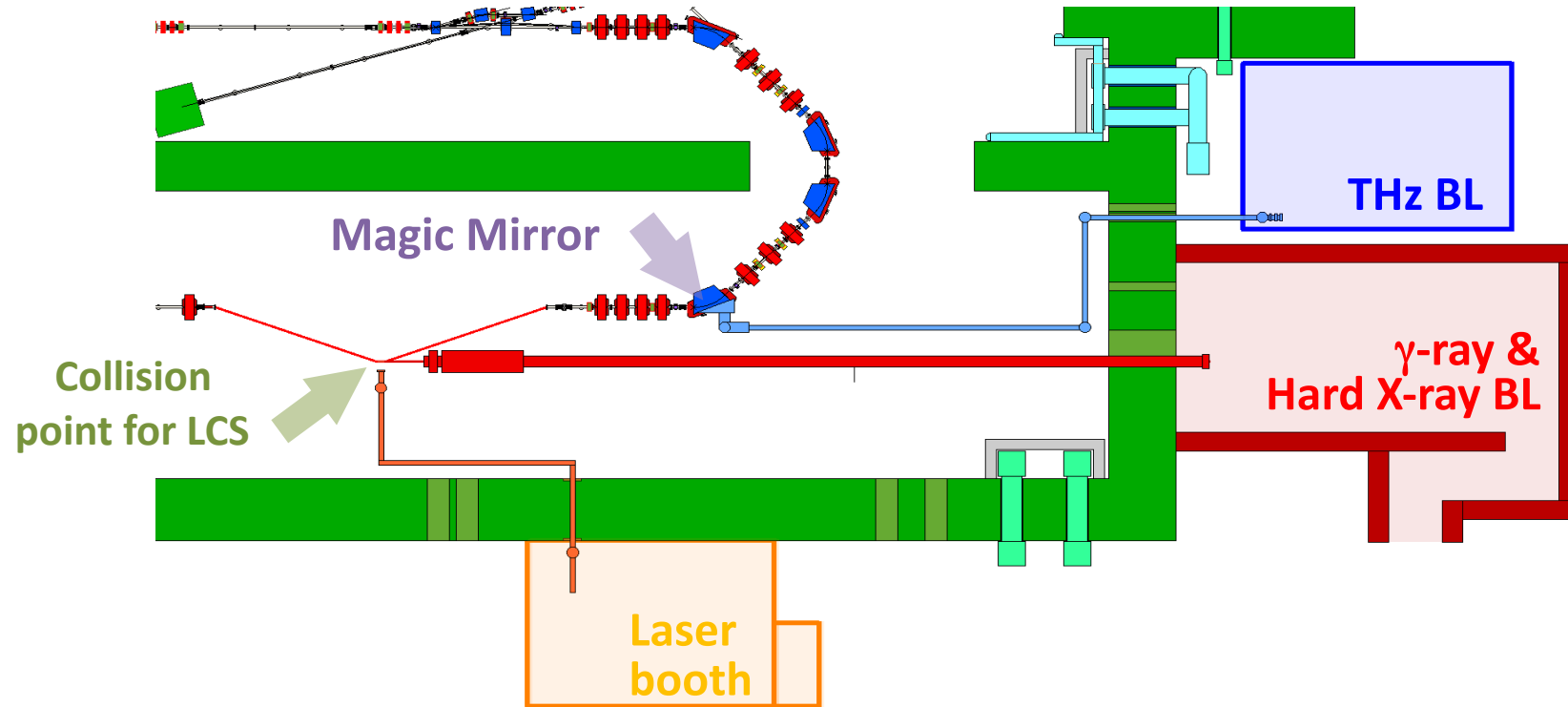
*This table may contain incorrect data.

cf. C. Bressler and M. Chergui, Chem. Rev. **104**, 1781 (2004)

NW2A, PF-AR => LC x-ray, cERL;
what are the merits?

- Faster phenomena down to **~100 fs** will be targeted and detected.
- The **jitter** could be **excluded**, and the delay will be exactly sure as set in principle.
- The larger emittance gives us a wider range of DXAFS per shot.

2つのビームラインにおける利用研究



レーザーコンプトンX線ビームライン

共振器によるLCSを用いた高flux光源

■ 高視野と共振器による高fluxイメージング

90度衝突LCS散乱を利用したフェムト秒光源

■ 100fs準単色光を用いた時間分解X線実験

テラヘルツ光ビームライン

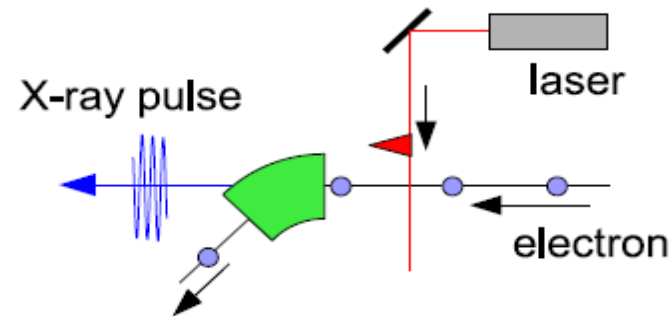
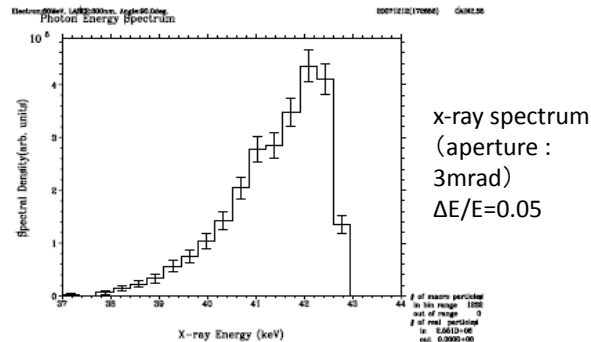
CSRを用いた高強度コヒーレントTHz光源

■ meV領域における電子状態変化の観測

■ コヒーレント性を利用したイメージング

■ フォノン励起用フェムト秒光源

X-ray beamline – ultrafast mode



Laser	
Wavelength	800 nm
Pulse energy	10 mJ
Frequency	1 kHz
Pulse width	50 fs
Beam size	20um

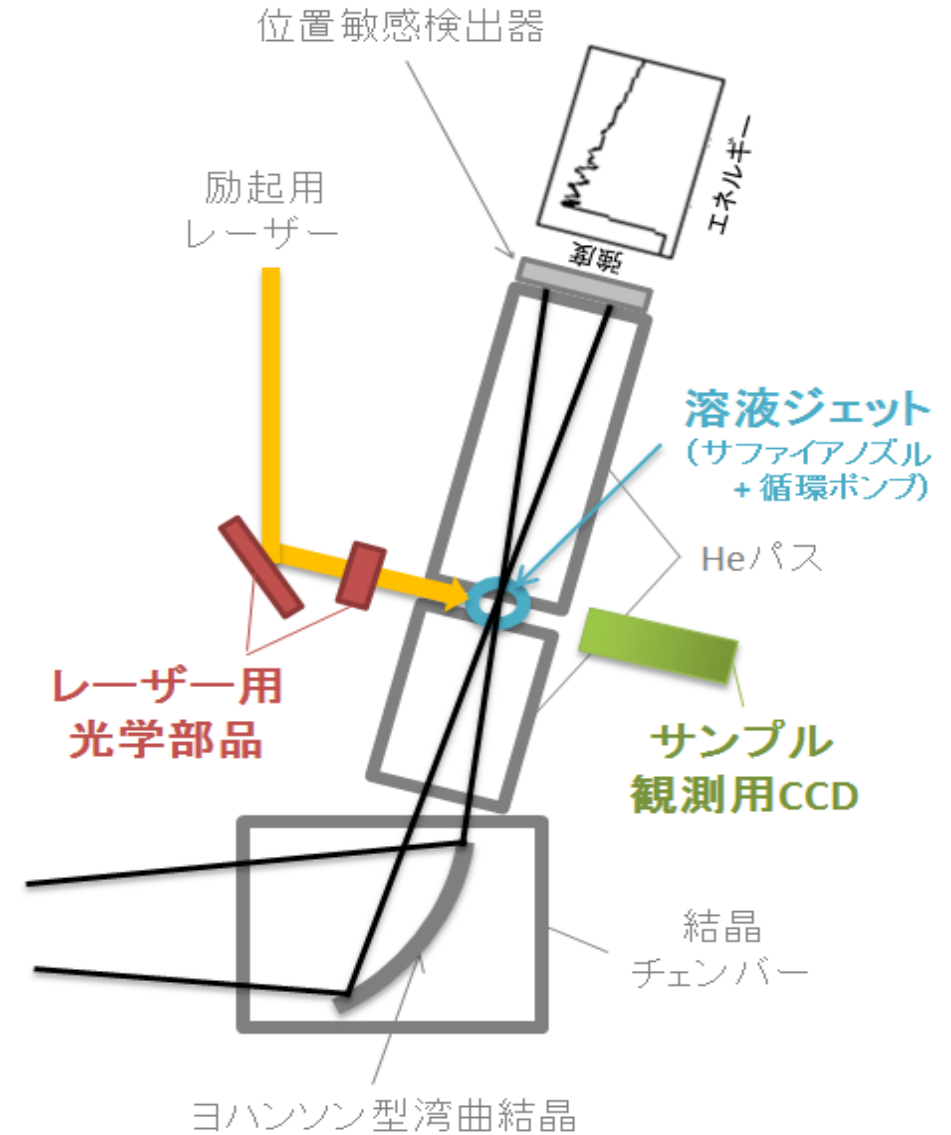
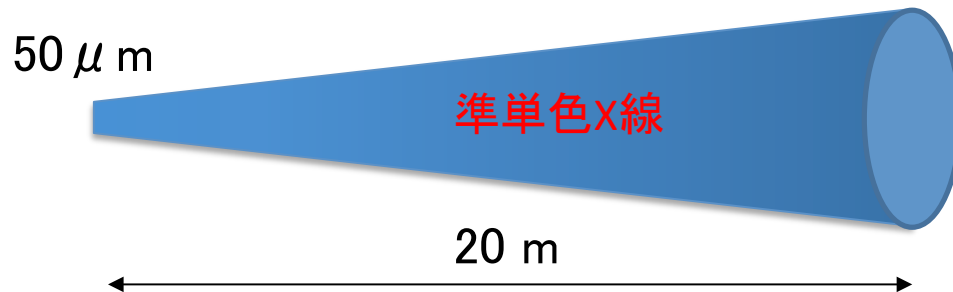
Electron bunch	
Energy	60 MeV
Charge	0.1 nC
Bunch width	1ps
Bunch size	20um
Emittance	1mm-mrad

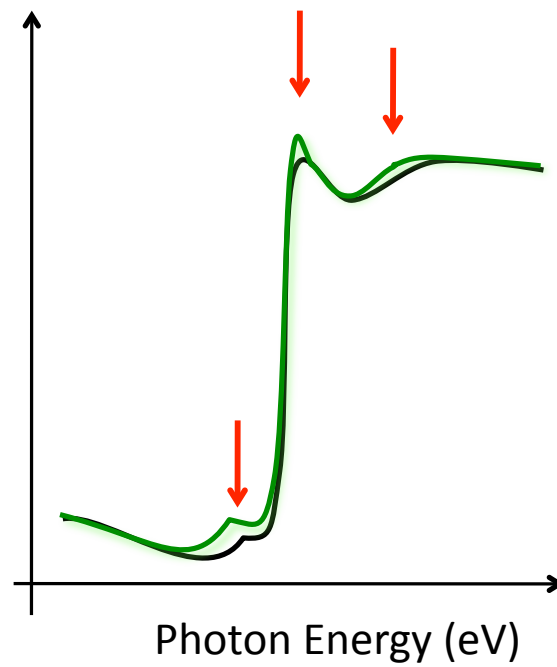
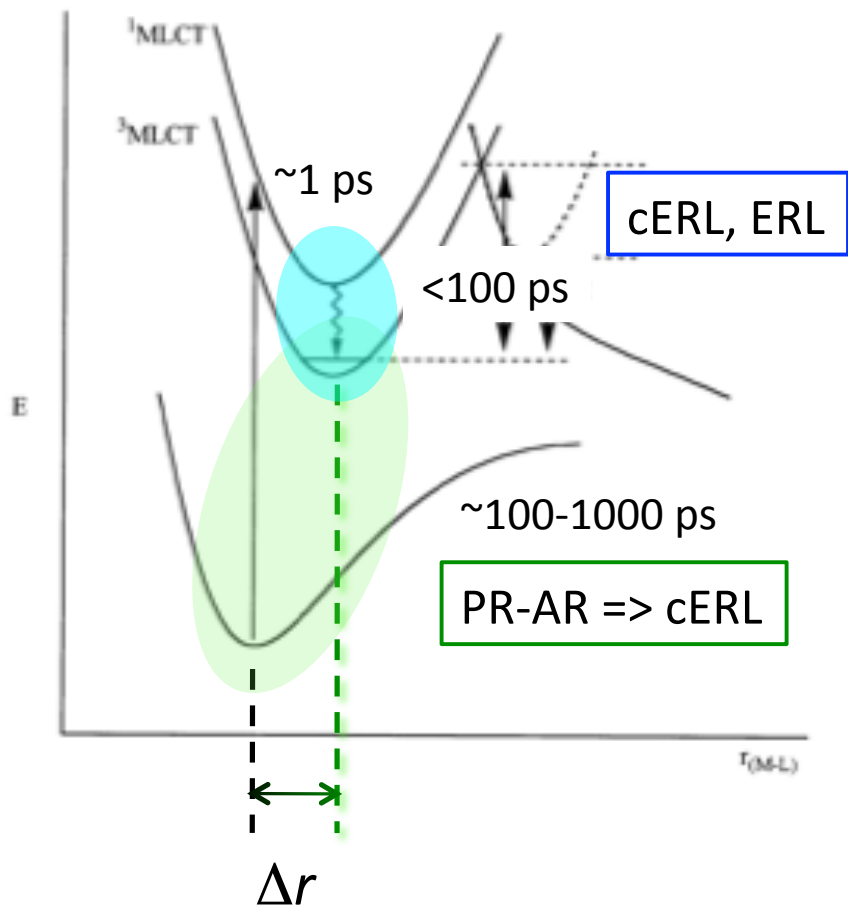
Laser-Compton X-ray	
Averaged X-ray Flux	3.9×10^7 phs/s • 100% bw
X-Ray pulse width	110 fs

コーンビームを用いた時間分解DXAFS

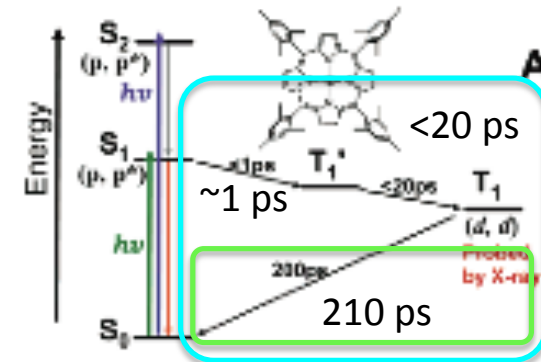
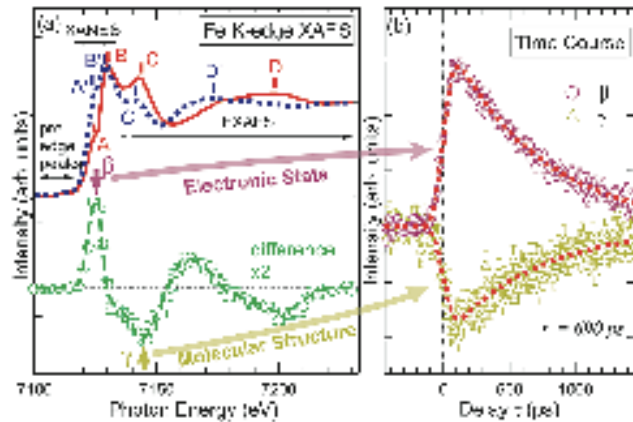
衝突点とサンプルの間(20m)
に5mradのコリメーターを設置

- 発光点の大きさ: $50\ \mu\text{m}$
- 準単色化 ($\Delta E/E \sim 0.1$)
- $\Phi 100\text{mm}$ のビームサイズ
- 光子密度: 5×10^6 photons/sec





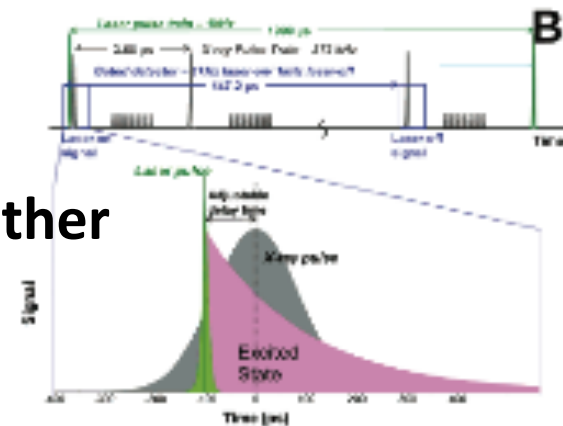
DXAFS at LC x-ray, cERL



The transient state will be captured

in the excellent time resolution of **~ 100 fs**

in spectra recorded by **ONE SHOT** after another



What we can do at LC x-ray of cERL

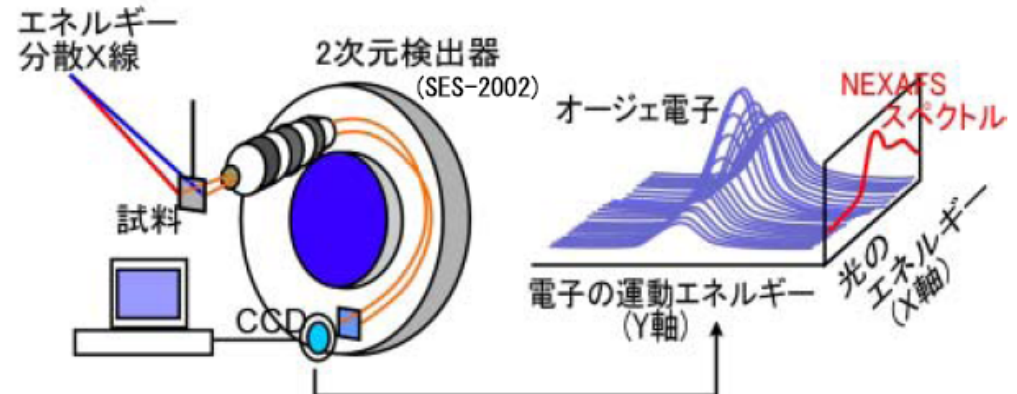
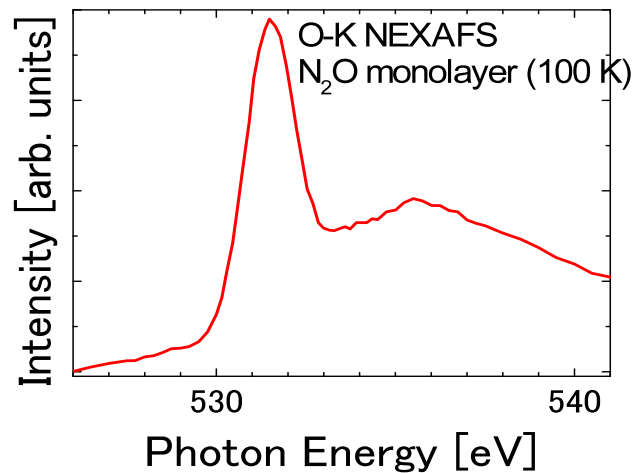
- Time-resolved, **Transient X-ray Absorption** spectroscopy by **DXAFS** with **$\Delta t = \sim 100$ fs**
- In principle, the **jitter free** measurements will be performed.
- The larger emittance, the larger size of the beam enables us to measure a wider range of XAFS per shot.

Then, do we need 3-GeV ERL? YES!!!!

- **Higher photon energy**
- **Much more flux:** huge repeated measurements are not required.
- Higher frequency of the ring, **1.3 GHz:** photons come **every 0.8 ns**, and “**movies**” of reactions will be captured in realistic conditions.
 - Not only Pump – Probe experiments
 - But also **Real time evolution** experiments

Current status of our time-resolved experiment

Disp-NEXAFS



several min/spectrum
→ **33 ms/spectrum**

→ 反応が速い室温以上でも
追跡可能に！

[*]

Dispersive NEXAFS法を用いて室温以上での
反応を表面分光法で調べる

[*] 小宇佐友香 (慶應大、近藤研), 修士論文発表スライド



Available time resolution & possible study

	Acquisition Rep rate	Period of real time observable reaction	Ratio (Period/Rep rate)
Current status: 16A at PF	33 ms (Video rate of the camera)	~100 s	$\sim 10^{3-4}$
Future: ERL	0.8 ns (Pulse interval)	(~100 ns)- 1 -10 μs	$\sim 10^{3-4}$

Real time observations of catalysts at very working temperature

For example...

How suitable!! Perfect!!

CO oxidation on Pt(111)

$$E_a = 0.5 - 0.7 \text{ eV}$$

RT => 600 - 900 K

(Ratio of k) = $10^4 - 10^8$

...maybe (^^;)

Summary

- Prospects of DXAFS at LCS X-ray station, cERL are presented.
 - **Laser Pump – DXAFS Probe** experiments are strongly recommended to perform.
 - $\Delta t = \sim 100$ fs, **Jitter free**, The wider range of XAFS
- cERL is a fancy machine, but 3-GeV ERL must be established
 - as **to shine mysteries of transition states** and to capture **real time “movies” of chemical reactions.**

Acknowledgments

- Dr. S. Pascarelli, Dr. O. Mathon @ESRF
- Prof. Ishitani & his group @ Tokyo Inst. of Tech.
- Prof. S. Adachi, Prof. S. Nozawa and Dr. T. Sato
- Prof. H. Kondoh, Ms. Y. Kousa @Keio Univ.
- Prof. Nomura, Prof. Nitani and Mr. Niwa